

On the characterization of MPA CVD diamond for fracture toughness measurements

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Methods

Double Torsion

$$K = P S_m \left(\frac{3}{S t^4 (1 - \nu) \psi} \right)^{1/2}$$

Failure to fracture in diamond disks: Fracture toughness & Integrity assessment

60 ITER disks, Ø70 mm, 1.11 mm

Brazing region
Aperture region

NO + 2 bar

Ø80 mm disk, optical

15 mm x 30 mm x 1.11 mm

µm

- [100 : 150]
- [150 : 200]
- [200 : 250]
- [250 : 300]
- [300 : 600]

from Ø150 mm disk, thermal

10 mm

Preliminary optical (GS)

Preliminary thermal (GS)

12 mm x 22 mm x 1.11 mm

- Microscopy
- Loss tangent
- EBSD
- XRD
- Raman
- Pillar splitting

Results

Microfeatures - 24 disks

33% 42% 25%

µm

- [100 : 150]
- [150 : 200]
- [200 : 250]
- [250 : 300]
- [300 : 600]

ρ_{micr.,braz.} / ρ_{micr.,aper.} < 3 ρ_{micr.,braz.} / ρ_{micr.,aper.} > 20

Disk GS

Aperture boundary
Brazing boundaries

~37 MPa
~48 MPa
~84 MPa
~56 MPa

σ₀ ~ 84 MPa
a ~ 320 µm
β ~ 1 (rough estimation)
K_I = β σ₀ (π a)^{1/2}
K_I ~ 2.6 MPa m^{1/2}
K_{IC} ~ 8 MPa m^{1/2} (Davies, J. Mater. Sci, 2004)

Disk/Ranges [µm]	Number of microfeatures in brazing region				
	100 - 150	150 - 200	200 - 250	250 - 300	300 - 600
S-T02	534	121	31	6	1
S-T03	299	53	12	4	1
S-T04	94	17	7	5	1
S-T05	447	82	21	7	0
S-T06	25	17	9	5	0
S-T17	1213	400	171	53	26
S-T09	326	71	11	4	2
S-T12	257	94	24	10	5
S-T08	164	27	15	10	1
S-T10	108	14	6	0	0
S-T13	82	13	4	2	1
S-T15	482	142	42	22	7
S-T16	80	10	1	1	0
S-T19	1422	580	255	102	64
S-T21	332	73	18	7	3
S-T23	1153	424	136	63	28
S-T14	264	69	14	4	1
S-T20	268	80	38	15	9
S-T24	1008	365	127	45	36
S-T27	452	101	27	4	1
S-T28	809	228	83	22	6
S-T30	40	15	6	10	1
S-T31	62	19	6	2	1
S-T33	85	21	6	0	1
Average	417	127	45	17	8

Optical, XRD sin²ψ method

Φ (°)	GS σ (MPa)	NS σ (MPa)
0	74.7 ± 112	-8.8 ± 47.9
45	-114 ± 88.7	93.9 ± 45.9
90	-84.6 ± 110	-67.5 ± 34.6

Intensity, arb. units vs Raman shift [cm⁻¹]

Counts vs Position (°2theta)

Optical quality GS - Sample #6
Optical quality NS - Sample #6

Peaks labeled: (111), (220), (311), (400), (331)

Preliminary samples

GS – grain size
Average by number ~ 50 µm
Average by area ~ 200 µm

NS – grain size
Average by number ~ 6 µm
Average by area ~ 9 µm

Laser cut from side

Laser cut from top

Finalize experimental setup design for manufacturing, complete microscopy activity for ITER disks, characterize real-size samples